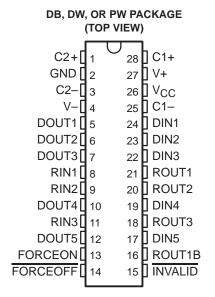
## MAX3238 3-V TO 5.5-V MULTICHANNEL RS-232 LINE DRIVER/RECEIVER

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- Meets or Exceeds the Requirements of TIA/EIA-232-F and ITU v.28 Standards
- Operates With 3-V to 5.5-V V<sub>CC</sub> Supply
- Always-Active Noninverting Receiver Output (ROUT1B)
- Operates up to 250 kbit/s
- Low Standby Current . . . 1 μA Typical
- External Capacitors . . . 4 × 0.1 μF
- Accepts 5-V Logic Input With 3.3-V Supply
- Designed to Be Interchangeable With Maxim MAX3238
- RS-232 Bus-Pin ESD Protection Exceeds ±15-kV Using Human-Body Model (HBM)
- Applications
  - Battery-Powered Systems, PDAs, Notebooks, Subnotebooks, Laptops, Palmtop PCs, Hand-Held Equipment, Modems, and Printers
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages



### description

The MAX3238 device consists of five line drivers, three line receivers, and a dual charge-pump circuit with  $\pm 15$ -kV ESD protection pin to pin (serial-port connection pins, including GND). The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between notebook and subnotebook computer applications. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. In addition, the device includes an always-active noninverting output (ROUT1B), which allows applications using the ring indicator to transmit data while the device is powered down. These devices operate at data signaling rates up to 250 kbit/s, and at a maximum of 30-V/ $\mu$ s driver output slew rate.

Flexible control options for power management are featured when the serial port and driver inputs are inactive. The auto-powerdown plus feature functions when FORCEON is low and  $\overline{FORCEOFF}$  is high. During this mode of operation, if the device does not sense valid signal transitions on all receiver and driver inputs for 30 s, the built-in charge-pump and drivers are powered down, reducing the supply current to 1  $\mu$ A. By disconnecting the serial port or placing the peripheral drivers off, auto-powerdown plus occurs if there is no activity in the logic levels for the driver inputs. Auto-powerdown plus can be disabled when FORCEON and  $\overline{FORCEOFF}$  are high. With auto-powerdown plus enabled, the device automatically activates once a valid signal is applied to any receiver or driver input.  $\overline{INVALID}$  is high (valid data) if any receiver input voltage is greater than 2.7 V or less than -2.7 V, or has been between -0.3 V and 0.3 V for less than 30  $\mu$ s.  $\overline{INVALID}$  is low (invalid data) if all receiver input voltages are between -0.3 V and 0.3 V for more than 30  $\mu$ s. Refer to Figure 5 for receiver input levels.

The MAX3238C is characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C. The MAX3238I is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.



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#### **AVAILABLE OPTIONS**

	Р	ACKAGED DEVICES		
TA	SHRINK SMALL OUTLINE (DB)	SMALL OUTLINE (DW)	THIN SHRINK SMALL OUTLINE (PW)	
0°C to 70°C	MAX3238CDB	MAX3238CDW	MAX3238CPW	
-40°C to 85°C	MAX3238IDB	MAX3238IDW	MAX3238IPW	

The DB, DW, and PW packages are available taped and reeled. Add the suffix R to device type (e.g., MAX3238CDBR).

#### **Function Tables**

#### **EACH DRIVER**

		INI	PUTS	OUTPUT	
DIN	FORCEON	FORCEOFF	TIME ELAPSED SINCE LAST RIN OR DIN TRANSITION	DOUT	DRIVER STATUS
Х	Х	L	X	Z	Powered off
L	Н	Н	Х	Н	Normal operation with
Н	Н	Н	X	L	auto-powerdown plus disabled
L	L	Н	<30 s	Н	Normal operation with
Н	L	Н	<30 s	L	auto-powerdown plus enabled
L	L	Н	>30 s	Z	Powered off by
Н	L	Н	>30 s	Z	auto-powerdown plus feature

H = high level, L = low level, X = irrelevant, Z = high impedance

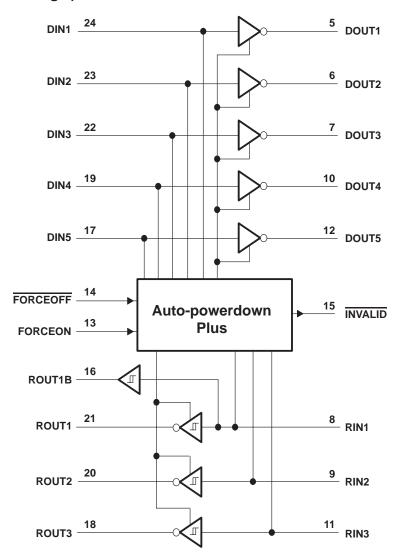
#### **EACH RECEIVER**

		INP	UTS	OUTP	UTS	
RIN2	RIN1, RIN3–RIN5	FORCEOFF	TIME ELAPSED SINCE LAST RIN OR DIN TRANSITION	ROUT1B	ROUT	RECEIVER STATUS
L	Х	L	Х	L	Z	Powered off while
Н	Χ	L	X	Н	Z	ROUT1B is active
L	L	Н	<30 s	L	Н	
L	Н	Н	<30 s	L	L	Normal operation with
Н	L	Н	<30 s	н	Н	auto-powerdown plus
Н	Н	Н	<30 s	Н	L	disabled/enabled
Open	Open	Н	>30 s	L	Н	

H = high level, L = low level, X = irrelevant, Z = high impedance (off), Open = input disconnected or connected driver off



# logic diagram (positive logic)



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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V <sub>CC</sub> (see Note 1)	0.3 V to 6 V
Positive output supply voltage range, V+ (see Note 1)	0.3 V to 7 V
Negative output supply voltage range, V– (see Note 1)	0.3 V to –7 V
Supply voltage difference, V+ – V– (see Note 1)	13 V
Input voltage range, V <sub>I</sub> : Driver (FORCEOFF, FORCEON)	
Receiver	
Output voltage range, V <sub>O</sub> : Driver	– 13.2 V to 13.2 V
Receiver (INVALID)	$\dots$ -0.3 V to V <sub>CC</sub> + 0.3 V
Package thermal impedance, θ <sub>JA</sub> (see Note 2): DB package	62°C/W
DW package	46°C/W
PW package	62°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltages are with respect to network GND.
  - 2. The package thermal impedance is calculated in accordance with JESD 51.

## recommended operating conditions (see Note 3 and Figure 6)

			_	MIN	NOM	MAX	UNIT
	Supply voltage		V <sub>CC</sub> = 3.3 V	3	3.3	3.6	V
	Supply voltage		$V_{CC} = 5 V$	4.5	5	5.5	V
\/	/IH Driver and control high-level input voltage DIN, FORCEOFF, FORCEON		V <sub>CC</sub> = 3.3 V	2			V
VIH	briver and control high-level input voltage	DIN, FORCEOFF, FORCEON	V <sub>CC</sub> = 5 V	2.4			V
VIL	Driver and control low-level input voltage	DIN, FORCEOFF, FORCEON				0.8	V
٧ <sub>I</sub>	Driver and control input voltage	DIN, FORCEOFF, FORCEON		0		5.5	V
٧ <sub>I</sub>	Receiver input voltage			-25		25	V
TA	Operating free-air temperature		MAX3238C	0		70	°C
'A	Operating nee-an temperature		MAX3238I	-40		85	O

Testing supply conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3  $V \pm 0.15$  V; C1–C4 = 0.22  $\mu$ F at  $V_{CC}$  = 3.3  $V \pm 0.3$  V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu F$  at VCC = 5 V  $\pm$  0.5 V.

## electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAME	TER	TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
II	Input leakage current	FORCEOFF, FORCEON			±0.01	±1	μΑ
		Auto-powerdown plus disabled	No load, FORCEOFF and FORCEON at V <sub>CC</sub>		0.5	2	mA
Icc	Supply current	Powered off	No load, FORCEOFF at GND		1	10	
.00	Cappy callon	Auto-powerdown plus enabled	No load, FORCEOFF at V <sub>CC</sub> , FORCEON at GND, All RIN are open or grounded		1	10	μΑ

 $<sup>\</sup>ddagger$  All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C.

NOTE 3: Testing supply conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V ± 0.15 V; C1–C4 = 0.22  $\mu$ F at V<sub>CC</sub> = 3.3 V ± 0.3 V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu F$  at V\_CC = 5 V  $\pm$  0.5 V.



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#### **DRIVER SECTION**

## electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAMETER	TES	ST CONDITIONS		MIN	TYP†	MAX	UNIT
Vон	High-level output voltage	All DOUT at $R_L = 3 \text{ k}\Omega$ to	All DOUT at R <sub>L</sub> = 3 k $\Omega$ to GND			5.4		V
VOL	Low-level output voltage	All DOUT at R <sub>L</sub> = 3 k $\Omega$ to GND		-5	-5.4		V	
I <sub>IH</sub>	High-level input current	$V_I = V_{CC}$				±0.01	±1	μΑ
IIL	Low-level input current	V <sub>I</sub> at GND				±0.01	±1	μА
laa.		V <sub>CC</sub> = 3.6 V,	VO = 0 V			±35	±60	mA
los	Short-circuit output current <sup>‡</sup>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0 V			±40	±100	IIIA
r <sub>o</sub>	Output resistance	$V_{CC}$ , V+, and V- = 0 V,	$V_O = \pm 2 V$		300	10M		Ω
l <sub>off</sub>	Output leakage current	FORCEOFF = GND,	$V_0 = \pm 12 \text{ V},$	$V_{CC} = 0 \text{ to } 5.5 \text{ V}$			±25	μА

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$  or  $V_{CC} = 5 \text{ V}$ , and  $T_A = 25^{\circ}\text{C}$ .

NOTE 3: Testing supply conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.15 V; C1–C4 = 0.22  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V  $\pm$  0.5 V.

## switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAMETER	TEST CON	TEST CONDITIONS			MAX	UNIT
	Maximum data rate	C <sub>L</sub> = 1000 pF, One DOUT switching,	$R_L = 3 k\Omega$ , See Figure 1	250			kbit/s
t <sub>sk(p)</sub>	Pulse skew§	C <sub>L</sub> = 150 pF to 2500 pF	R <sub>L</sub> = 3 kΩ to 7 kΩ, See Figure 2		100		ns
SR(tr)	Slew rate, transition region	$V_{CC} = 3.3 \text{ V},$ $R_{I} = 3 \text{ k}\Omega \text{ to 7 k}\Omega$	C <sub>L</sub> = 150 pF to 1000 pF	6		30	V/us
J SK(II)	(see Figure 1)	$R_L = 3 \text{ k}\Omega \text{ to } 7 \text{ k}\Omega$	C <sub>L</sub> = 150 pF to 2500 pF	4		30	ν/μ5

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$  or  $V_{CC} = 5 \text{ V}$ , and  $T_A = 25^{\circ}\text{C}$ .

NOTE 3: Testing supply conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.15 V; C1–C4 = 0.22  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu F$  at V  $_{CC}$  = 5 V  $\pm$  0.5 V.

<sup>‡</sup> Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.

<sup>§</sup> Pulse skew is defined as |tplH - tpHL| of each channel of the same device.

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#### RECEIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vон	High-level output voltage	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> – 0.6 V	V <sub>CC</sub> – 0.1 V		V
VOL	Low-level output voltage	I <sub>OL</sub> = 1.6 mA			0.4	V
\/	Positive-going input threshold voltage	V <sub>CC</sub> = 3.3 V		1.5	2.4	V
VIT+	Positive-going input tilleshold voltage	V <sub>CC</sub> = 5 V		1.8	2.4	V
\/	Negative going input threshold voltage	V <sub>CC</sub> = 3.3 V	0.6	1.2		V
VIT-	Negative-going input threshold voltage	V <sub>CC</sub> = 5 V	0.8	1.5		V
V <sub>hys</sub>	Input hysteresis (V <sub>IT+</sub> – V <sub>IT</sub> –)			0.3		V
loff	Output leakage current (except ROUT1B)	FORCEOFF = 0 V		±0.05	±10	μΑ
rį	Input resistance	$V_{I} = \pm 3 \text{ V to } \pm 25 \text{ V}$	3	5	7	kΩ

 $<sup>^{\</sup>dagger}$  All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C.

NOTE 3: Testing supply conditions are C1–C4 = 0.1  $\mu$ F at V $_{CC}$  = 3.3 V  $\pm$  0.15 V; C1–C4 = 0.22  $\mu$ F at V $_{CC}$  = 3.3 V  $\pm$  0.3 V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu$ F at V $_{CC}$  = 5 V  $\pm$  0.5 V.

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3)

	PARAMETER	TEST CONDITIONS	MIN TYPT MA	XX UNIT
tPLH	Propagation delay time, low- to high-level output	C <sub>I</sub> = 150 pF, See Figure 3	150	ns
tPHL	Propagation delay time, high- to low-level output	CL = 150 pr, See rigule 5	150	ns
t <sub>en</sub>	Output enable time	$C_1 = 150 \text{ pF}, R_1 = 3 \text{ k}\Omega, \text{ See Figure 4}$	200	ns
tdis	Output disable time	CL = 150 pr, KL = 5 ks2, See Figure 4	200	ns
tsk(p)	Pulse skew <sup>‡</sup>	See Figure 3	50	ns

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C.

NOTE 3: Testing supply conditions are C1–C4 = 0.1  $\mu$ F at V $_{CC}$  = 3.3 V  $\pm$  0.15 V; C1–C4 = 0.22  $\mu$ F at V $_{CC}$  = 3.3 V  $\pm$  0.3 V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu$ F at V $_{CC}$  = 5 V  $\pm$  0.5 V.



<sup>‡</sup> Pulse skew is defined as |tpLH - tpHL| of each channel of the same device.

#### **AUTO-POWERDOWN PLUS SECTION**

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
V <sub>T+(valid)</sub>	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V <sub>CC</sub>			2.7	V
V <sub>T</sub> –(valid)	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V <sub>CC</sub>	-2.7			V
VT(invalid)	Receiver input threshold for INVALID low-level output voltage	FORCEON = GND, FORCEOFF = V <sub>CC</sub>	-0.3		0.3	V
VOH	INVALID high-level output voltage	$I_{OH} = -1 \text{ mA}$ , FORCEON = GND, FORCEOFF = $V_{CC}$	V <sub>CC</sub> - 0.6			V
VOL	INVALID low-level output voltage	$I_{OL} = 1.6 \text{ mA}$ , FORCEON = GND, FORCEOFF = $V_{CC}$			0.4	V

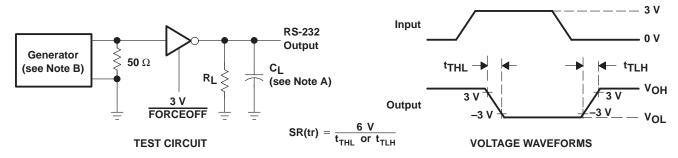
<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$  or  $V_{CC} = 5 \text{ V}$ , and  $T_A = 25^{\circ}\text{C}$ .

## switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	MIN	TYP†	MAX	UNIT
<sup>t</sup> valid	Propagation delay time, low- to high-level output		0.1		μs
<sup>t</sup> invalid	Propagation delay time, high- to low-level output		50		μs
t <sub>en</sub>	Supply enable time		25		μs
t <sub>dis</sub>	Receiver or driver edge to auto-powerdown plus	15	30	60	s

 $<sup>\</sup>overline{\dagger}$  All typical values are at  $V_{CC} = 3.3 \text{ V or } V_{CC} = 5 \text{ V}$ , and  $T_A = 25^{\circ}C$ .

## PARAMETER MEASUREMENT INFORMATION

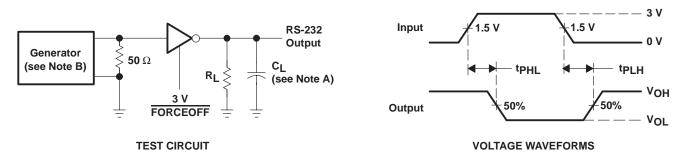


NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns.  $t_f \le 10$  ns.

Figure 1. Driver Slew Rate

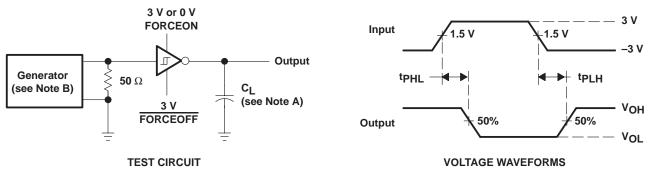
#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_f \le 10$  ns,  $t_f \le 10$  ns.

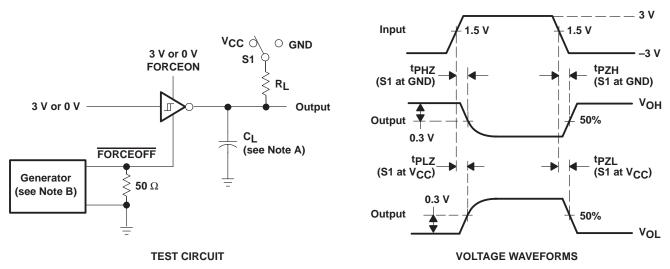
Figure 2. Driver Pulse Skew



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. The pulse generator has the following characteristics:  $Z_O = 50~\Omega,~50\%$  duty cycle,  $t_\Gamma \le 10~\text{ns}.~t_f \le 10~\text{ns}.$ 

Figure 3. Receiver Propagation Delay Times



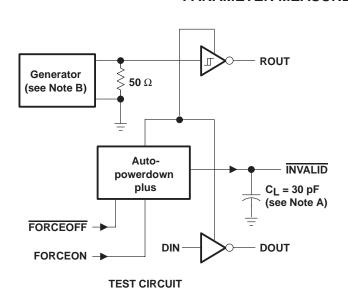
NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

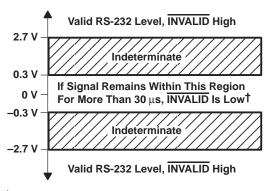
- B. The pulse generator has the following characteristics:  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_\Gamma \le 10$  ns.  $t_f \le 10$  ns.
- C.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- D. tpzL and tpzH are the same as ten.

Figure 4. Receiver Enable and Disable Times



#### PARAMETER MEASUREMENT INFORMATION





† Auto-powerdown plus disables drivers and reduces supply current to 1 μA.

- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_O$  = 50  $\Omega$ , 50% duty cycle,  $t_f \le 10$  ns,  $t_f \le 10$  ns.

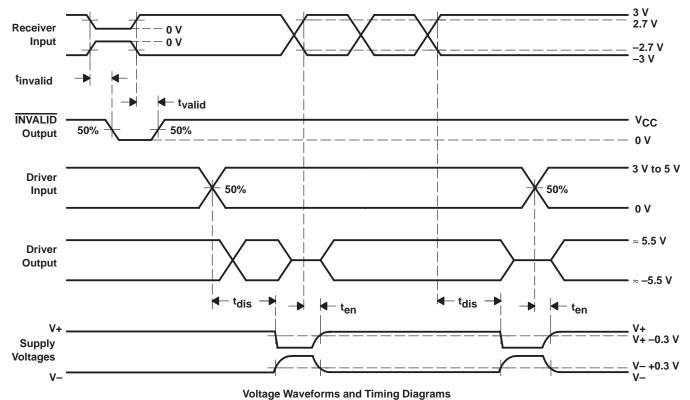
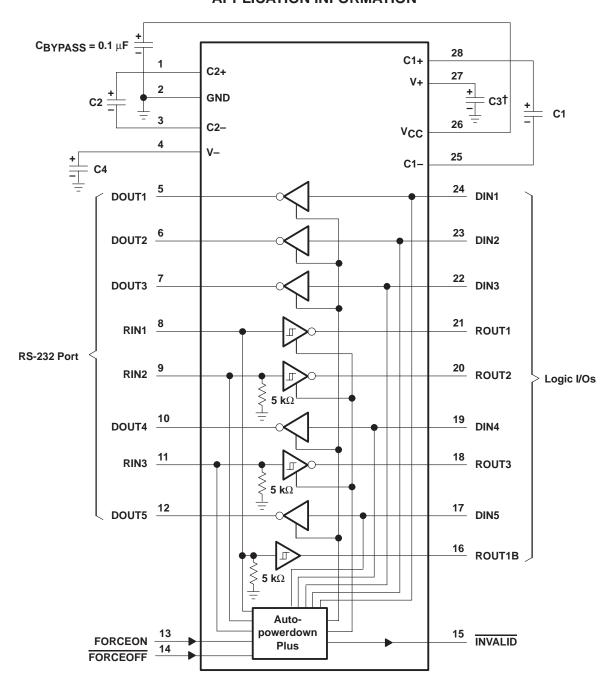


Figure 5. INVALID Propagation Delay Times and Supply Enabling Time



#### **APPLICATION INFORMATION**



 $^\dagger$  C3 can be connected to VCC or GND.

NOTE A: Resistor values shown are nominal.

**V<sub>CC</sub>** vs CAPACITOR VALUES

VCC	C1	C2, C3, and C4
$  \begin{array}{c} 3.3 \text{ V} \pm 0.15 \text{ V} \\ 3.3 \text{ V} \pm 0.3 \text{ V} \\ 5 \text{ V} \pm 0.5 \text{ V} \\ 3 \text{ V to } 5.5 \text{ V} \\ \end{array} $	0.1 μF 0.22 μF 0.047 μ F 0.22 μF	0.1 μF 0.22 μF 0.33 μF 1 μF

Figure 6. Typical Operating Circuit and Capacitor Values



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